Notice of References Cited Application/Control No. 10/046,117 Examiner Backhean Tiv Applicant(s)/Patent Under Reexamination YARED ET AL. Art Unit Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-4,853,843 A	08-1989	Ecklund, Denise J.	707/203
*	В	US-5,491,821 A	02-1996	Kilis, Danny	717/146
*	С	US-5,748,188 A	05-1998	Hu et al.	715/853
*	D	US-5,890,176 A	03-1999	Kish et al.	715/511
*	E	US-5,991,771 A	11-1999	Falls et al.	707/202
*	F	US-6,125,400 A	09-2000	Cohen et al.	709/247
*	G	US-6,199,198 B1	03-2001	Graham, Stephen	717/105
*	Н	US-2002/0029375 A1	03-2002	Mlynarczyk et al.	717/108
*	ı	US-2002/0116412 A1	08-2002	Barnes et al.	707/513
*	J	US-2002/0188950 A1	12-2002	Soloff et al.	725/63
*	К	US-2003/0123537 A1	07-2003	Yona et al.	375/240.01
*	L	US-6,141,792	10-2000	Acker et al.	717/116
*	М	US-6,721,942 B1	04-2004	Sievert, James A.	717/137

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0	A				
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	her, Edition or Volume, Pertinent Pages)		
	U				
	V .				
	w				
	х				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.